

Power MOSFET

PRODUCT SUMMAI	RY			
V _{DS} (V)	750			
$R_{DS(on)}(\Omega)$	V _{GS} = 10 V	6.5		
Q _g (Max.) (nC)	38			
Q _{gs} (nC)	5.0			
Q _{gd} (nC)	21			
Configuration	Single			

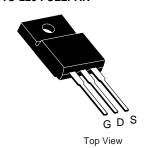
FEATURES

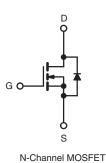
- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC





TO-220 FULLPAK





PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			V _{DS}	750	V
Gate-Source Voltage		V _{GS}	± 20]	
Continuous Drain Current	\/ at 10 \/	$T_C = 25 ^{\circ}C$ $T_C = 100 ^{\circ}C$		1.8	
Continuous Drain Current	V _{GS} at 10 V	T _C = 100 °C	I _D	1.2	Α
Pulsed Drain Current ^a			I _{DM}	7.2	
Linear Derating Factor				0.43	W/°C
Single Pulse Avalanche Energy ^b			E _{AS}	180	mJ
Repetitive Avalanche Current ^a			I _{AR}	1.8	А
Repetitive Avalanche Energy ^a			E _{AR}	5.4	mJ
aximum Power Dissipation $T_C = 25 ^{\circ}C$		P _D	35	W	
Peak Diode Recovery dV/dtc			dV/dt	2.0	V/ns
Operating Junction and Storage Temperature Range	e		T _J , T _{stg}	- 55 to + 150	ာင
Soldering Recommendations (Peak Temperature)	for	10 s		300 ^d	
Mounting Toyaus	6-32 or M3 screw			10	lbf ⋅ in
Mounting Torque				1.1	N⋅m

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. V_{DD} = 50 V, starting T_J = 25 °C, L = 104 mH, R_g = 25 Ω , I_{AS} = 1.8 A (see fig. 12). c. I_{SD} ≤ 1.8 A, dI/dt ≤ 80 A/µs, V_{DD} ≤ 600, T_J ≤ 150 °C.

- d. 1.6 mm from case.



THERMAL RESISTANCE RATI	NGS			
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	62	
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50	-	°C/W
Maximum Junction-to-Case (Drain)	R_{thJC}	-	2.3	

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		750	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference t	to 25 °C, I _D = 1 mA	-	0.98	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V$	_{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	V _G	_S = ± 20 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 80	V _{DS} = 800 V, V _{GS} = 0 V		-	100	μΑ
		V _{DS} = 640 V, V	V _{DS} = 640 V, V _{GS} = 0 V, T _J = 125 °C		-	500	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 1.1 A ^b	-	6.5	-	Ω
Forward Transconductance	9 _{fs}	V _{DS} = 10	00 V, I _D = 1.1 A ^b	0.80	-	-	S
Dynamic				1		•	
Input Capacitance	C _{iss}	$V_{GS} = 0 \text{ V}, \\ V_{DS} = 25 \text{ V},$		-	530	-	pF
Output Capacitance	C _{oss}			-	150	-	
Reverse Transfer Capacitance	C _{rss}	f = 1.0 I	MHz, see fig. 5	-	90	-	
Total Gate Charge	Qg			-	-	38	
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$I_D = 1.8 \text{ A}, V_{DS} = 400 \text{ V},$ see fig. 6 and 13^b	-	-	5.0	nC
Gate-Drain Charge	Q _{gd}			-	-	21	
Turn-On Delay Time	t _{d(on)}			-	8.2	-	
Rise Time	t _r	$V_{DD} = 400 \text{ V, } I_D = 1.8 \text{ A,}$ $R_g = 18 \Omega, R_D = 230 \Omega, \text{ see fig. } 10^b$		-	17	-	ns
Turn-Off Delay Time	t _{d(off)}			-	58	-	
Fall Time	t _f			-	27	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	-11
Internal Source Inductance	L _S			-	7.5	-	nH
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	showing the	MOSFET symbol showing the		-	1.8	A
Pulsed Diode Forward Current ^a	I _{SM}	integral reverse p - n junction diode		-	-	7.2	
Body Diode Voltage	V_{SD}	T _J = 25 °C, I _S = 1.8 A, V _{GS} = 0 V ^b		-	-	1.4	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 1.8 A, dI/dt = 100 A/μs ^b		-	380	570	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	0.94	1.4	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-	-on is do	minated b	by L _S and	L _D)	

Notes

2

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 µs; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

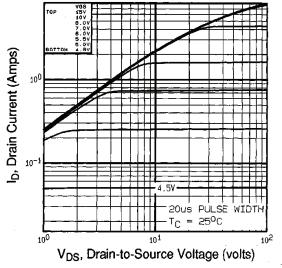


Fig. 1 - Typical Output Characteristics, $T_C = 25$ °C

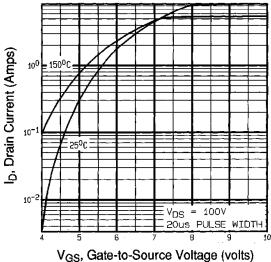


Fig. 3 - Typical Transfer Characteristics

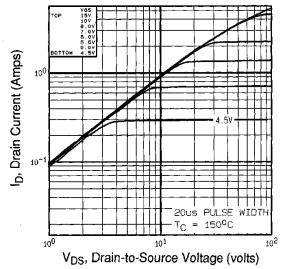


Fig. 2 - Typical Output Characteristics, T_C = 150 °C

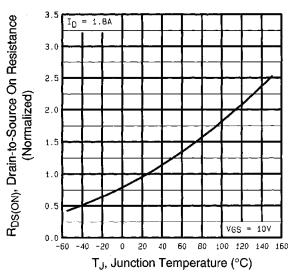


Fig. 4 - Normalized On-Resistance vs. Temperature



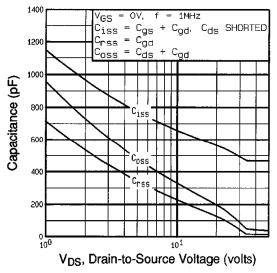


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

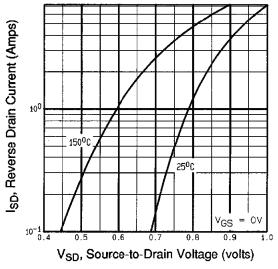


Fig. 7 - Typical Source-Drain Diode Forward Voltage

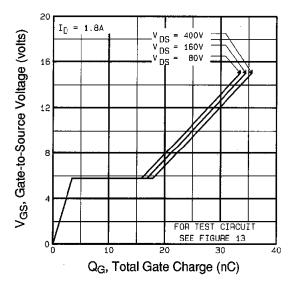


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

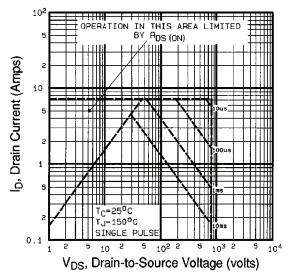


Fig. 8 - Maximum Safe Operating Area



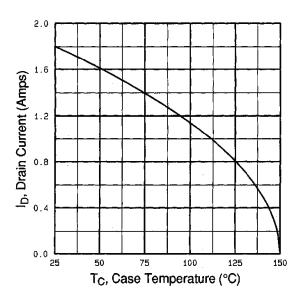


Fig. 9 - Maximum Drain Current vs. Case Temperature

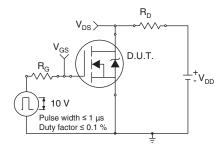


Fig. 10a - Switching Time Test Circuit

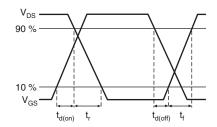


Fig. 10b - Switching Time Waveforms

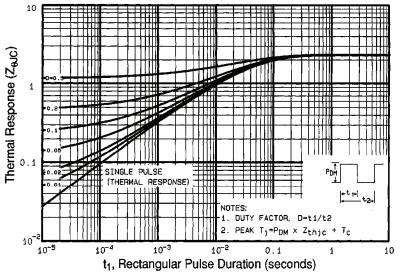
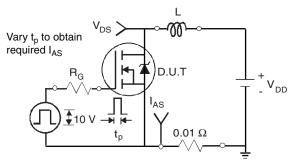


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case





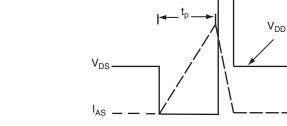


Fig. 12a - Unclamped Inductive Test Circuit

Fig. 12b - Unclamped Inductive Waveforms

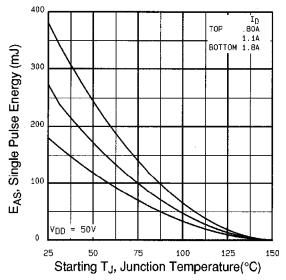


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

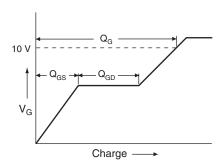


Fig. 13a - Basic Gate Charge Waveform

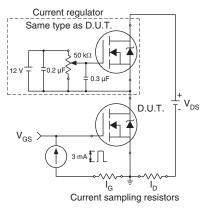
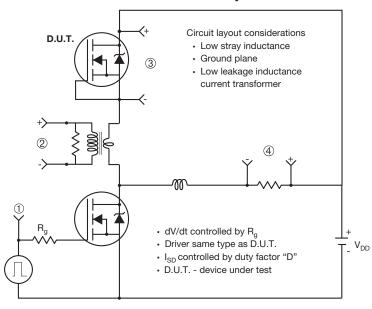


Fig. 13b - Gate Charge Test Circuit



7

Peak Diode Recovery dV/dt Test Circuit



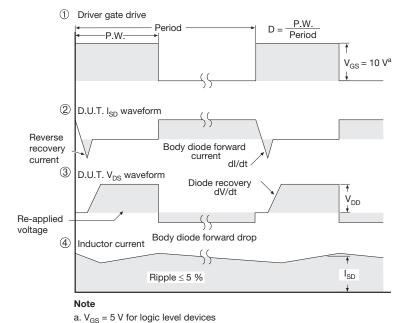
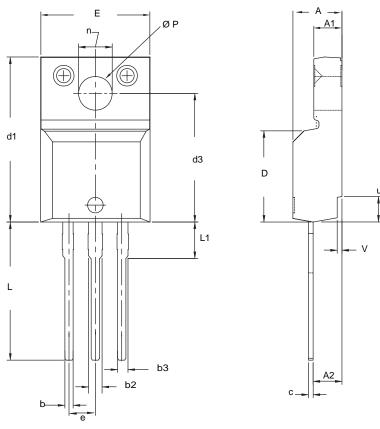


Fig. 14 - For N-Channel



TO-220 FULLPAK (HIGH VOLTAGE)



	MILLIN	METERS	INCHES	
DIM.	MIN.	MAX.	MIN.	MAX.
Α	4.570	4.830	0.180	0.190
A1	2.570	2.830	0.101	0.111
A2	2.510	2.850	0.099	0.112
b	0.622	0.890	0.024	0.035
b2	1.229	1.400	0.048	0.055
b3	1.229	1.400	0.048	0.055
С	0.440	0.629	0.017	0.025
D	8.650	9.800	0.341	0.386
d1	15.88	16.120	0.622	0.635
d3	12.300	12.920	0.484	0.509
E	10.360	10.630	0.408	0.419
е	2.54	BSC	0.100) BSC
L	13.200	13.730	0.520	0.541
L1	3.100	3.500	0.122	0.138
n	6.050	6.150	0.238	0.242
ØΡ	3.050	3.450	0.120	0.136
u	2.400	2.500	0.094	0.098
V	0.400	0.500	0.016	0.020

DWG: 5972

Notes

- To be used only for process drawing.
 These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads.
 All critical dimensions should C meet C_{pk} > 1.33.
 All dimensions include burrs and plating thickness.
 No chipping or package damage.



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